# **MOSFET** – Power, Single N-Channel

40 V, 0.45 mΩ, 558 A

# NTMTSOD4N04C

#### **Features**

- Small Footprint (8x8 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- Power 88 Package, Industry Standard
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	40	V
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	558	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		394.8	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	244.0	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		122.0	
Continuous Drain	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	79.8	Α
Current R <sub>θJA</sub> (Notes 1, 2, 3)		T <sub>A</sub> = 100°C		56.4	
Power Dissipation		T <sub>A</sub> = 25°C	$P_{D}$	5.0	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		2.5	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to + 175	°C
Source Current (Body Diode)			Is	203.4	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 70 A)			E <sub>AS</sub>	4454	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.61	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	30	

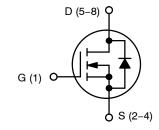
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



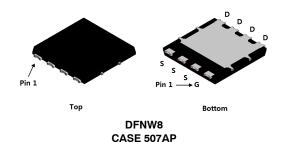
#### ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	0.45 m $\Omega$ @ 10 V	558 A



**N-CHANNEL MOSFET** 



#### **MARKING DIAGRAM**



XXX = Device Code

(8 A-N characters max)

A = Assembly Location

WL = 2-digit Wafer Lot Code

Y = Year Code

WW = Work Week Code

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	-				-		•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				7.78		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$ , $V_{J} = 25 °C$				10	
		V <sub>DS</sub> = 40 V	T <sub>J</sub> = 125°C			250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		2.0		4.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-8.49		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		0.38	0.45	mΩ
Forward Transconductance	9 <sub>F</sub> s	V <sub>DS</sub> =15 V, I <sub>D</sub> = 50 A			300		S
CHARGES, CAPACITANCES & GATE RESISTANCE							
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 0.1 MHz, V <sub>DS</sub> = 20 V			16500		pF
Output Capacitance	C <sub>OSS</sub>				8310		
Reverse Transfer Capacitance	C <sub>RSS</sub>				390		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 50 A			251		
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 50 A			40.0		nC
Gate-to-Source Charge	Q <sub>GS</sub>				62.6		
Gate-to-Drain Charge	$Q_{GD}$				49.0		
Plateau Voltage	$V_{GP}$				4.08		V
Gate Resistance	R <sub>G</sub>				0.9		Ω
SWITCHING CHARACTERISTICS (Note	5)				•		•
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 20 V, $I_{D}$ = 50 A, $R_{G}$ = 6 $\Omega$			55.2		
Rise Time	t <sub>r</sub>				50.8		- ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				200		
Fall Time	t <sub>f</sub>				78.7		
DRAIN-SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 50 A	T <sub>J</sub> = 25°C		0.75	1.2	,,,
			T <sub>J</sub> = 125°C		0.58		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			120		
Charge Time	ta				60		ns
Discharge Time	t <sub>b</sub>				60		
Reverse Recovery Charge	Q <sub>RR</sub>				338		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

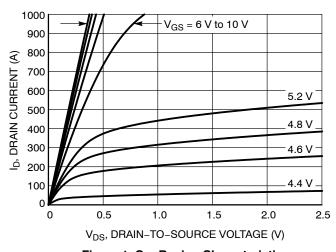


Figure 1. On-Region Characteristics

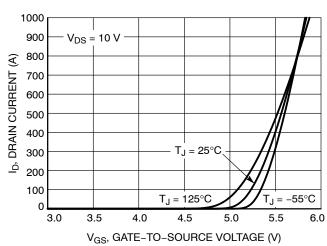


Figure 2. Transfer Characteristics

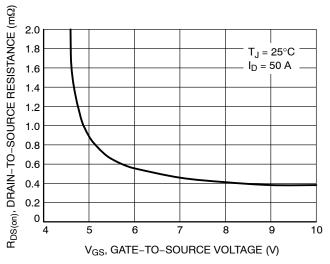


Figure 3. On-Resistance vs. Gate-to-Source Voltage

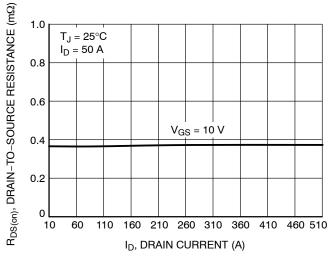


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

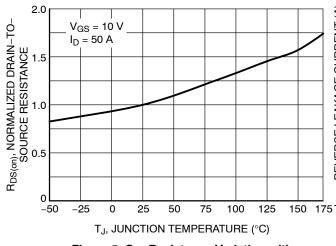


Figure 5. On–Resistance Variation with Temperature

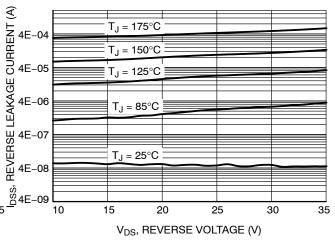


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

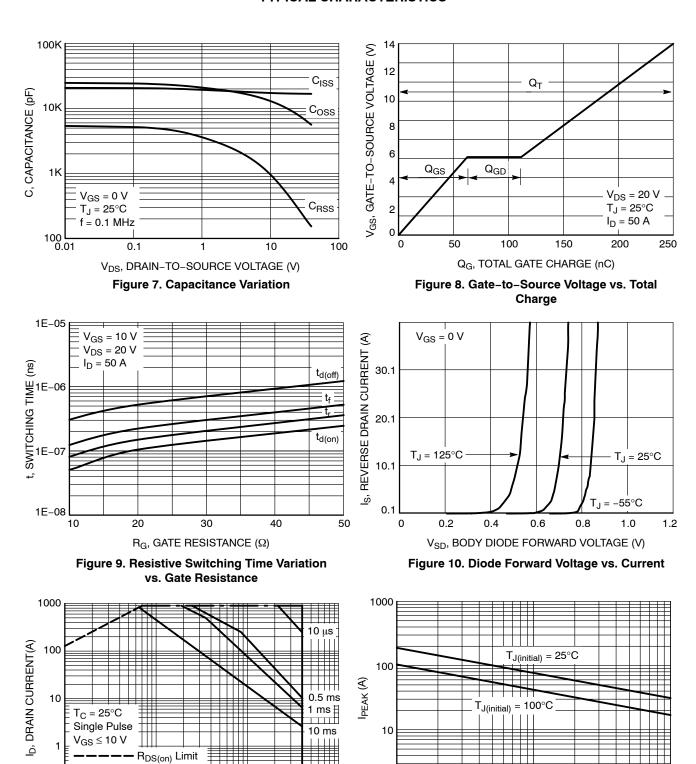


Figure 11. Maximum Rated Forward Biased Safe Operating Area

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

10

Thermal Limit Package Limit

0.1

0.1

TIME IN AVALANCHE (s)

Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

0.0001

0.001

100

0.00001

#### **TYPICAL CHARACTERISTICS**

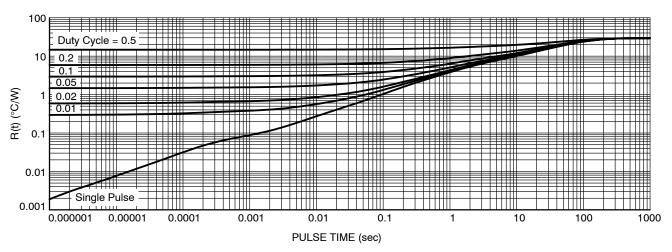


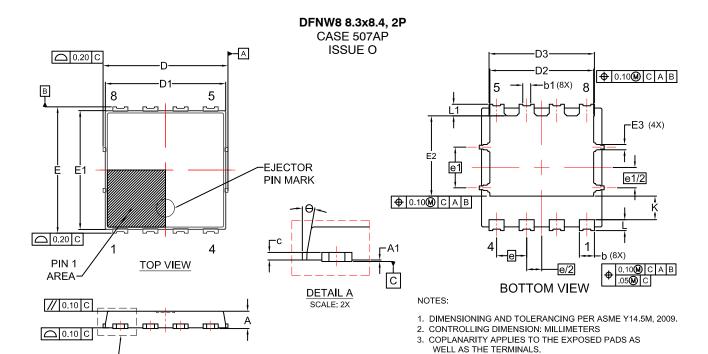
Figure 13. Thermal Characteristics

# **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMTS0D4N04CTXG	0D4N04C	POWER 88 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **PACKAGE DIMENSIONS**



8.10 KEEP OUT AREA

1.33 1 1.15

9.42 1.50 1.28

1.25 1.28

FRONT VIEW

SEE DETAIL A

RECOMMENDED LAND PATTERN

MILLIMETERS DIM MIN. NOM. MAX. Α 1.00 1.10 1.20 Α1 0.00 0.05 1.00 b 0.90 1.10 b1 0.43 0.53 0.63 0.23 0.28 0.33 С D 8.20 8.30 8.40 D1 7.90 8.00 8.10 D2 6.80 6.90 7.00 D3 7.00 7.10 6.90 F 8.30 8.40 8.50 E1 7.80 7.90 8.00 E2 5.24 5.34 5.44 E3 0.25 0.35 0.45 2.00 BSC е e/2 1.00 BSC 2.70 BSC e1 1.35 BSC e1/2 Κ 1.50 1.57 1.70 0.64 0.74 0.84 L1 0.67 0.77 0.87 θ 0° 12°

4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH,

SEATING PLANE IS DEFINED BY THE TERMINALS.
"A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.

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